

# $W \rightarrow e\nu$ cross-section measurement at CMS with the first $3\text{pb}^{-1}$ of pp collision data

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## Introduction (I)

- In this presentation I will discuss only a part of my contribution to the recent CMS  $W \rightarrow e\nu$  cross-section measurement

CMS ECAL:  
data certification,  
ECAL software

CMS EGAMMA:  
Electron Id, Supercluster  
cleaning, electron  
efficiency, egamma  
skimming

CMS EWK GROUP:  
Wev and Zee studies:  
electron efficiency,  
signal extraction, event  
and electron selection,  
software and ntuple  
production

### Other research work:

Stochastic thermostats: Phys. Rev. B**78**, 094305 (2008),  
J. Phys.: Cond. Matt. **22**, 074205 (2010)

Scanning Tunneling Microscopy: Phys. Rev. B**78**, 165302 (2008)  
Optics (Solitons in LHM): Phys. Rev. E**79**, 037601 (2009)

## Introduction (II)

- Major CMS Responsibilities:
  - Contact for CMS Egamma Electron Selections (Oct 09 till present)
  - ECAL data certification expert (Aug 09 till present)
  - EWK Wenu/Zee software contact, ntuple production (May 09 till present)
  - Co-editor in CMS PAS EGM-10-001, Section for Electron Isolation (January 2010).
  - Main contributor in CMS-PAS-EWK-09-004
  - Contact for Egamma skimming operations and EWK electron operations (CMS October 09 Exercise)
  - Contact for the CMS electron efficiency (May 08-Oct08)

## Overview

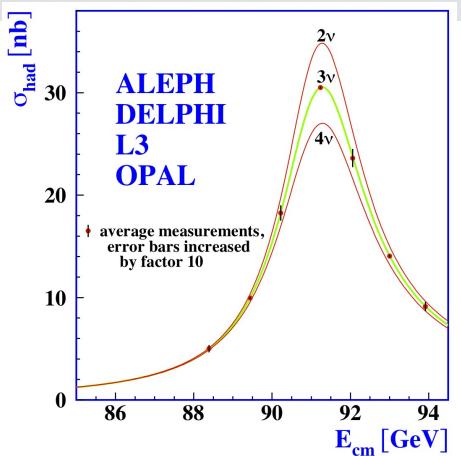
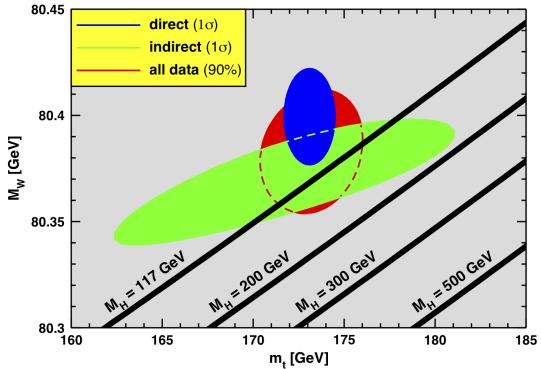
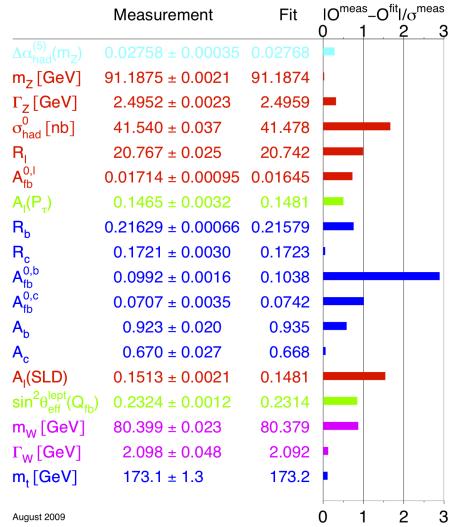
- Introduction: Weak Vector Bosons
  - $W\rightarrow e\nu$  channel
- CMS Experiment
- Overview of the Cross-Section Measurement
- $W\rightarrow e\nu$  Event Selection
  - Electron Selection
  - Tuning with a Genetic Algorithm
  - Tuning with the “Iterative Technique”
- Electron Selection Efficiency
- Signal Extraction
  - Data-driven jet template
  - Extrapolation-based signal extraction
- Cross-Section Results
- Outlook

## Introduction: Weak Vector Bosons

- The weak vector bosons ( $W, Z$ ) have been discovered through their production in  $p\bar{p}$  collisions and their leptonic decays (UA1 and UA2, 1983).
- Since then the measurement of their properties have contributed to the establishment of the Standard Model.  
Few examples follow:

# Introduction: Weak Vector Bosons

- Number of Neutrino Species
- Higgs mass constraint from W and top-quark mass



- Electroweak precision tests (mostly from precision Z measurements)

## Introduction: Weak Vector Bosons

- In pp collisions weak vector bosons play a very important role in physics and performance studies. Some examples:
  - W+jets, Z+jets, multiboson production is an important background to new or rare SM physics
  - Top-quark physics:  $t \rightarrow Wb$ ; Higgs physics:  $H \rightarrow ZZ$ ,  $H \rightarrow WW$
  - Energy scale calibration using precisely known Z mass
  - W is a major source of prompt leptons and real missing transverse energy (MET)

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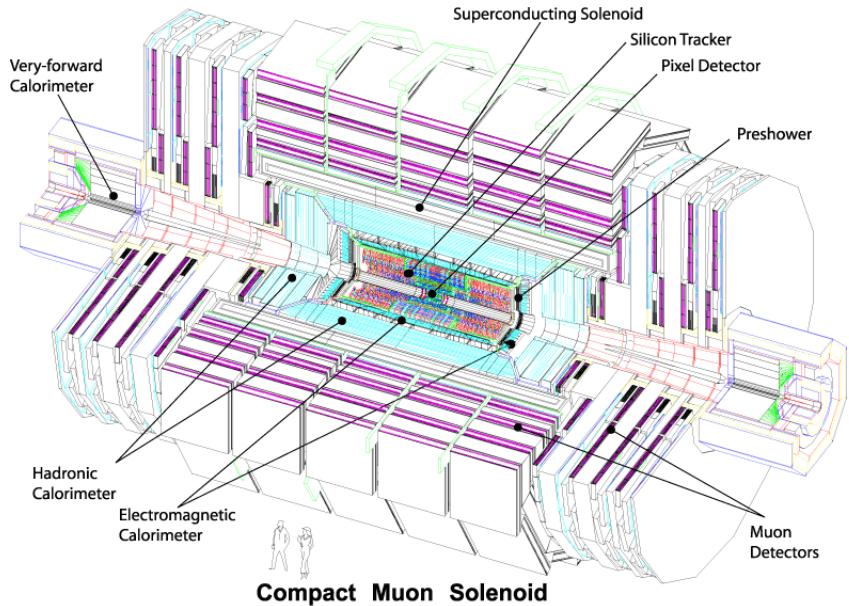
**Very important tool for lepton and MET commissioning, which is the most important use of the measurement that is discussed in this talk**

## Introduction: $W \rightarrow e\nu$ process

- $W \rightarrow e\nu$  decay is the most abundant source of high-pT electrons and high MET events
  - Cross section of  $\sim 10\text{nb}$  or  $\sim 5000$  good electrons ( $p_T > 20\text{GeV}/c$ ) per  $\text{pb}^{-1}$  in CMS
- Very useful in commissioning of
  - electron reconstruction and identification
  - MET
- Some physics measurements are also possible
  - $\text{pp} \rightarrow W\text{X}; W \rightarrow e\nu$  cross-section measurement is a test of perturbative QCD
    - » Can also be used as a luminosity estimator
  - The ratio of  $W$  and  $Z$  production cross sections can give a precise (but indirect) measurement of  $\Gamma_W$

## The CMS Experiment

- General purpose detector designed to measure the output of LHC pp (and heavy ion) collisions

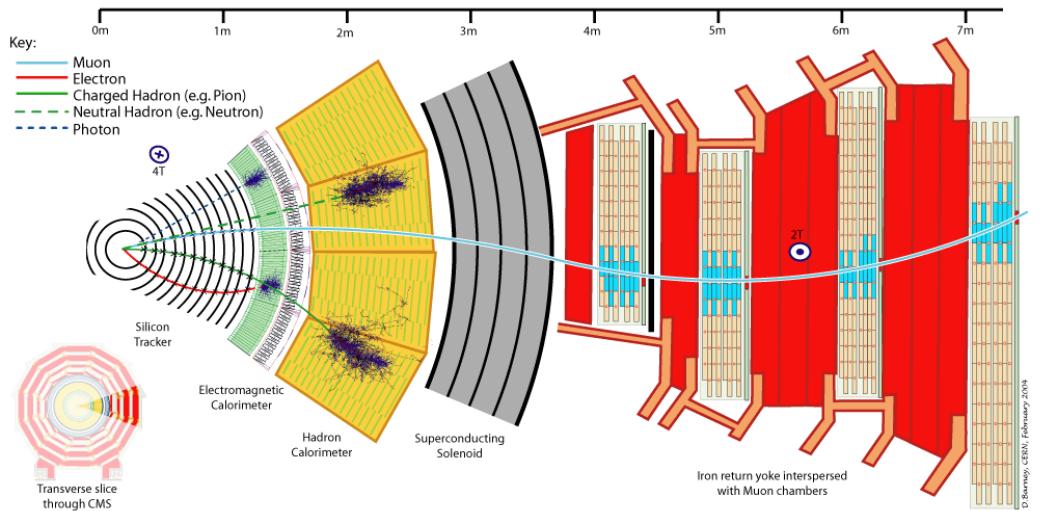
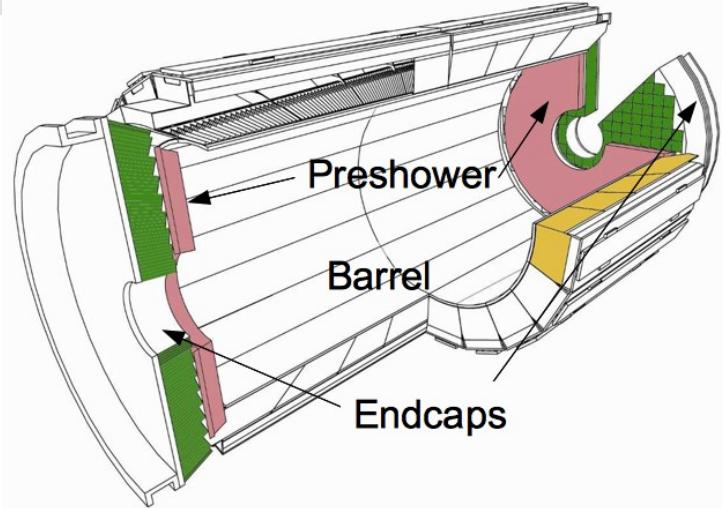


### Basic features:

- Large solenoid magnet that encloses inner tracking and calorimetry systems
- All-silicon tracker
- Homogeneous electromagnetic calorimeter (ECAL)
- Hermetic calorimetric coverage (up to  $|\eta| < 6.5$  including the very forward calorimeters)

## The CMS Experiment

- CMS ECAL is a homogeneous lead tungstate crystal calorimeter
  - Designed to fit in the very compact CMS design
  - Good energy resolution (stochastic term  $\sim 3\%$  cf.  $\sim 10\%$  for the ATLAS LiAr ECAL)
- Example of typical particle interactions in CMS



# Overview of the Cross-section Measurement

- How to calculate a cross section

$$\sigma = \frac{N_{candidates} - N_{bkg}}{A \epsilon \int L dt}$$

Acceptance of kinematic cuts  
Estimated from simulation

Signal extraction/ bkg removal

Integrated luminosity:  
Measured with Hadronic  
Forward calorimeter, normalized  
from beam parameters

Efficiency of selection criteria

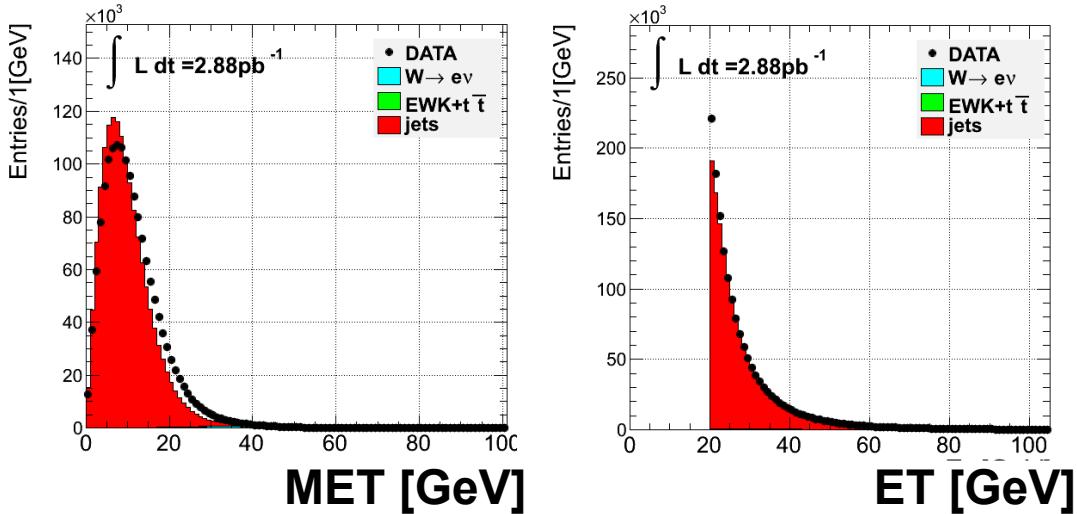
- In this talk I will focus on
  - W-candidate selection
  - Selection efficiency
  - Signal extraction

**Dataset in use corresponds to  $3\text{pb}^{-1}$**

**Measurement also described in  
CMS-PAPER-EWK-10-002  
(accepted by JHEP)**

# $W \rightarrow e\nu$ Event Selection

- $W \rightarrow e\nu$  events are characterized by a high- $pT$  electron ( $>20\text{GeV}/c$ ) and high MET ( $>20\text{GeV}$ )
- However, these criteria are not sufficient to extract a pure  $W$  sample
  - A single reconstructed electron sample contains a very small number of prompt electrons



Single reconstructed electron sample with electron ET $>20\text{GeV}$

## Sources of Electron Background

**Charged hadron -  $\pi^0$  overlap:**  
matched in space with a photon shower  
from  $\pi^0$

**Charged Hadrons showering early  
in ECAL, Charge exchange**  
( $\pi^+ n \rightarrow \gamma p$ )

Electrons from **conversions**  
or from **heavy flavor quark decays**  
(real electrons)

## W→eν Event Selection

- A method to enrich the single electron candidate sample with prompt electrons is to apply selection criteria on the electron candidates based on prompt electron properties like:
  - Isolation, Shower width and length, Track-ECAL cluster matching in  $\eta$  and  $\varphi$  directions ( $\Delta\eta$ ,  $\Delta\varphi$ )
  - Conversion rejection:  
search for a conversion partner track  
search for missing hits in the inner tracker layers, before the first hit that belongs to the electron candidate track

## Electron Selection

- Electron Selection: specific case of a classification problem
- Statistical theory tells us (Neyman-Pearson lemma) that the best classifier is the likelihood ratio
  - But difficult to calculate → approximations/use of other classifiers
  - Classification with cuts on variables will use this classifier

$$t(\vec{x}; \vec{c}) = \prod_i H(c_i - x_i), \quad c_i = \text{tunable parameter: cut value on electron property } x_i \\ H: \text{step function}$$

And the tuning of the classifier parameters ( $c_i$ , or “cuts”) is done by minimizing the function:

$$f(\vec{c}; \{\vec{x}\}, S) = \sum_{j \in Bkg} t(\vec{x}_j; \vec{c}) + \lambda \left( \sum_{i \in Sig} t(\vec{x}_i; \vec{c}) - S \right) \quad (1)$$

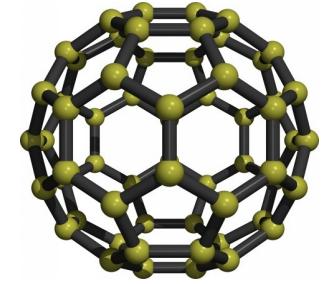
this effectively means that for a given signal, the cuts are chosen such that the background rejection is maximized – nothing new: exactly what the Neyman-Pearson lemma does, but in the case of a specific classifier

## Electron Selection Tuning

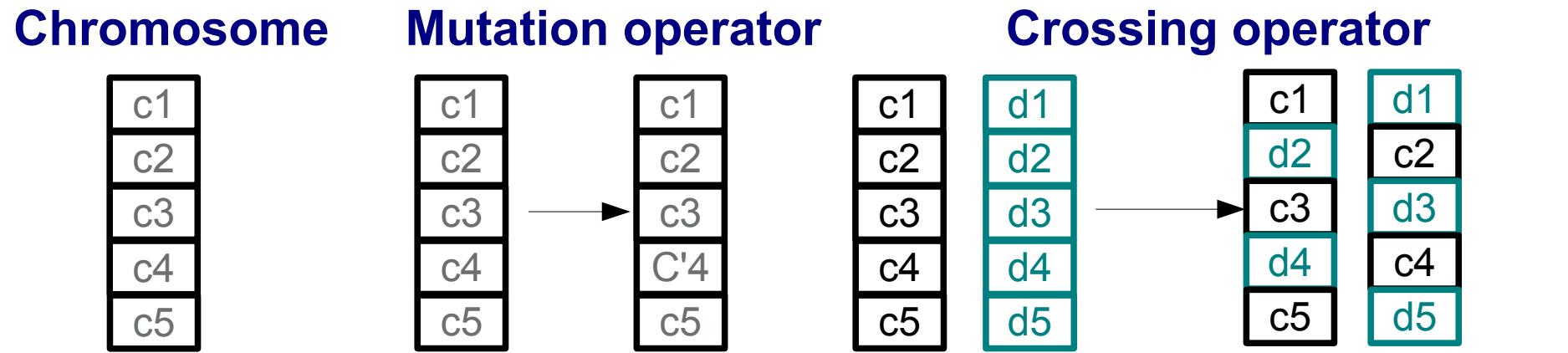
- There are many ways in the market to minimize Eq (1) of the previous slide
  - All of them start from the definition of signal and background samples, which are used for training/testing the classifier
  - In the following I will focus on describing 2 techniques that I have worked in the past
    - » Tuning based on a **Genetic Algorithm**
    - » Tuning based on an **Iterative Technique**

## Tuning with a Genetic Algorithm Implementation

- Genetic algorithm is a well established technique, first used in the 1960's
  - First application on physics in the 1990's with simulations of the fullerene structure
- Elements of the method
  - A potential solution to the problem is codified in a "chromosome", C in  $\bar{C}$
  - Definition of **operators**:
    - » Mutation  $M : \bar{C} \rightarrow \bar{C}$
    - » Crossing  $X : \bar{C} \times \bar{C} \rightarrow \bar{C} \times \bar{C}$
  - **Ordering principle**:  $C_1 > C_2$



# Tuning with a Genetic Algorithm Implementation



**Ordering through a “fitness function” :**  $r(\vec{x}) \times Gaus(\epsilon(\vec{x}) - \epsilon_0)$

Bkg rejection      Signal Efficiency      Target Efficiency

**Steps :** Create an initial chromosome population  $O(100)$   
Perform Mutations and Crossings to increase its size  
Keep the best members of the population  
Iterate

## The “Iterative Technique” for Selection Tuning

- The “Iterative Technique” is an approximation of the gradient descent minimization of Equation (1)

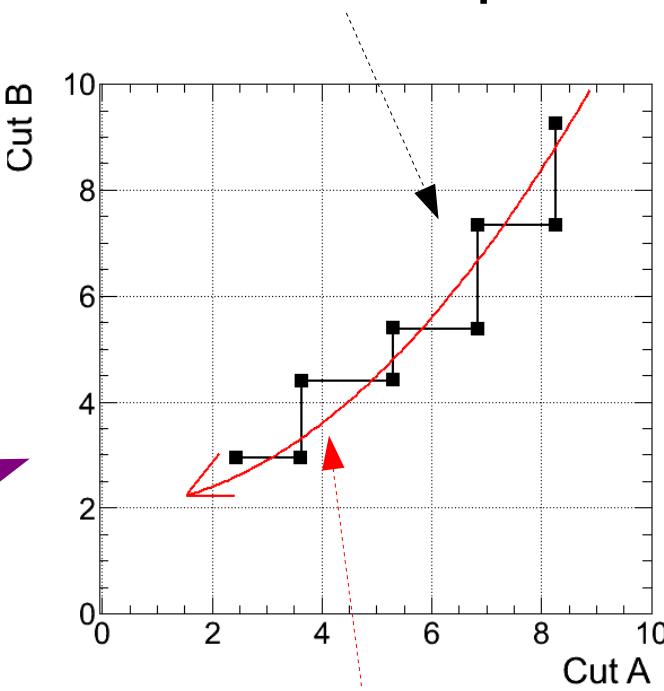
- It starts from a signal and background sample and a configuration with very loose cuts
- Steps:

1. define a target in bkg rejection that is slightly higher than the current one
2. find which **single** cut can achieve this bkg rejection target with the highest signal efficiency
3. change this single cut only to obtain a new selection
4. iterate

iterative algorithm concept  
illustration for a 2 cut case



path followed by the  
iterative technique



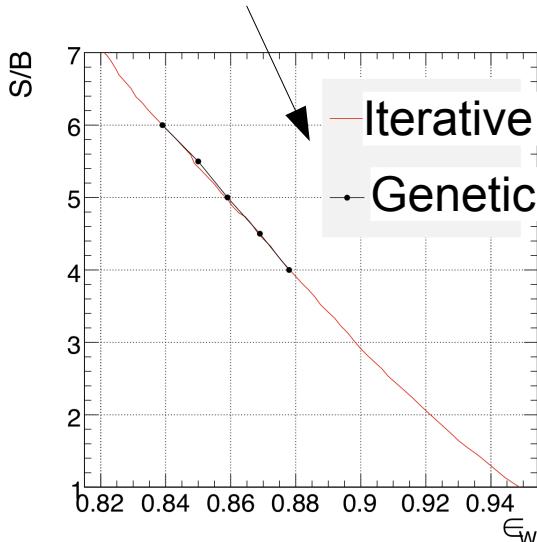
optimal curve that the algorithm  
tries to approximate

## The “Iterative Technique” for Selection Tuning

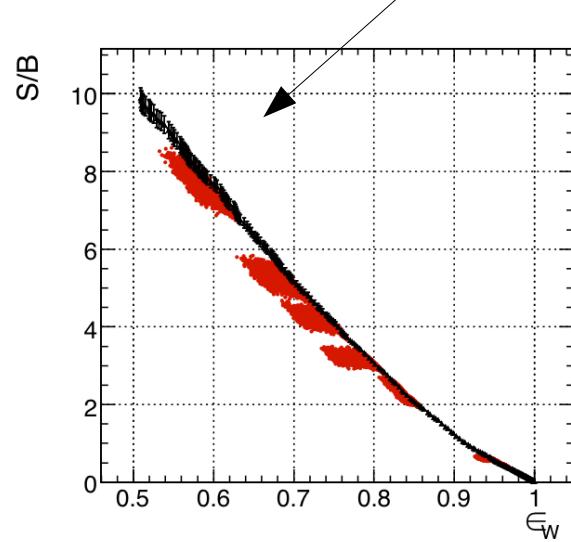
- Validation of the algorithm using simulation
  - Signal from  $W \rightarrow e\nu$ ; Bkg from jets+EWK bkg to  $W \rightarrow e\nu$

using electrons with  $ET > 30\text{GeV}$

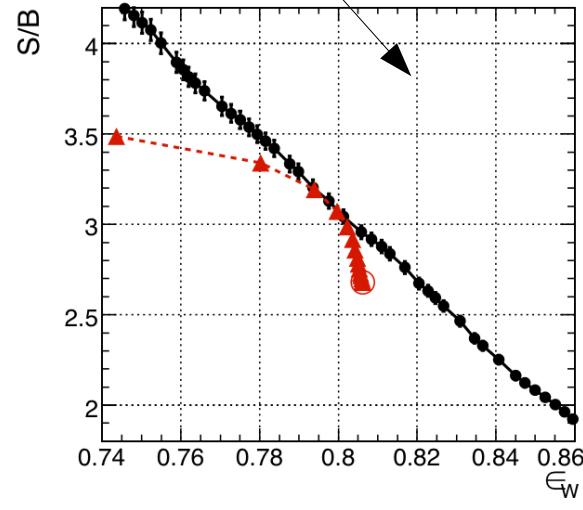
Comparison with the  
Genetic Algorithm Tuning



Randomly generated points, seeded by  
working points that the iterative produces



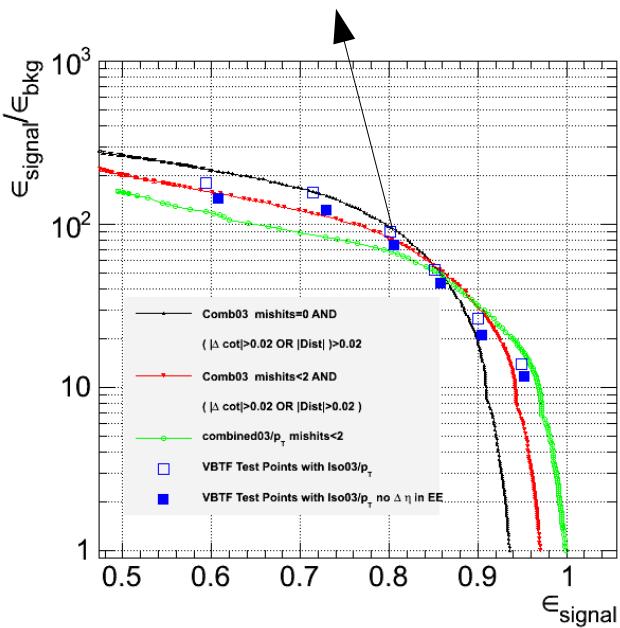
Moving the cut on a single variable  
(here ECAL isolation in EB)



## The “Iterative Technique” with MC Samples

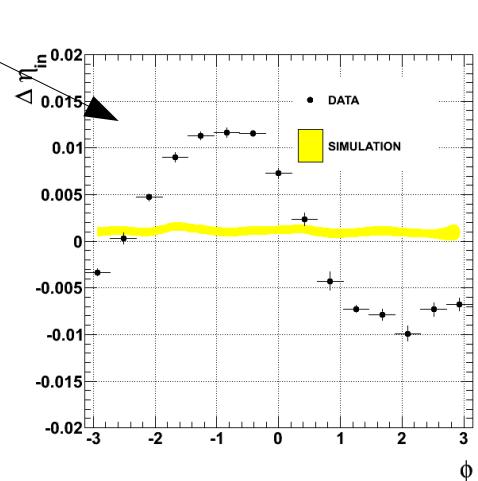
- The “Iterative Technique” was used with MC samples to tune electron selections for different conversion rejection tightnesses

“WP80” selection  
used for  $W \rightarrow e\nu$  cross section



- When the first data became available the simulation was found to describe electrons pretty well
  - » Modulo the ECAL Endcaps–tracker misalignment

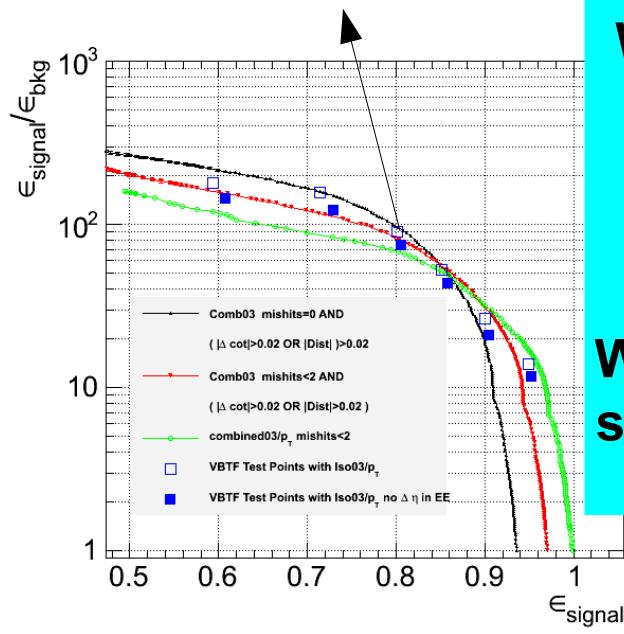
The MC-tuned electron selections have been used without the  $\Delta\eta$  cut in ECAL EE for electron identification in data throughout the first year of data taking for all CMS analyses that use electrons



# The “Iterative Technique” with MC Samples

- The “Iterative Technique” was used with MC samples to tune electron selections for different conversion rejection tightnesses

“WP80” selection  
used for  $W \rightarrow e\nu$  cross sec



All CMS analyses in 2010 with electrons have used one of these electron selections, e.g.

W and Z cross sections CMS-PAPER-EWK-10-002

Top quark production CMS-PAPER-TOP-10-001

Search for b' CMS-PAPER-EXO-10-018

W charge asymmetry CMS-PAPER-EWK-10-006

W polarization CMS-PAPER-EWK-10-014

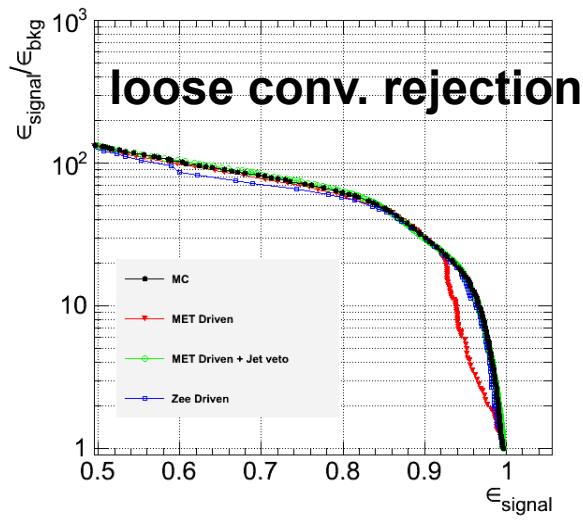
WW production observation CMS-PAS-EWK-10-009  
single-lepton SUSY searches (e.g. CMS-CR-10-030)

or data taking for all  
CMS analyses that use  
electrons



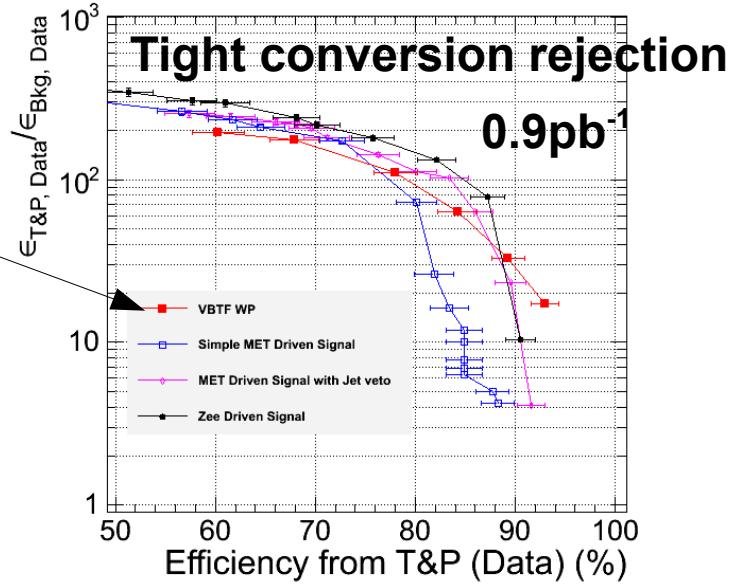
## Data Driven Selection Tuning with the “Iterative Technique”

- Data-driven definitions of signal/bkg samples are also possible from a single electron ( $ET > 20\text{GeV}$ ) sample:
  - Bkg:  $\text{MET} < 20\text{GeV}$
  - Signal: 3 different ways
    - »  $\text{MET} > 30\text{GeV}$
    - »  $\text{MET} > 30\text{GeV}$  plus jet veto
    - » electrons from  $Z\text{ee}$



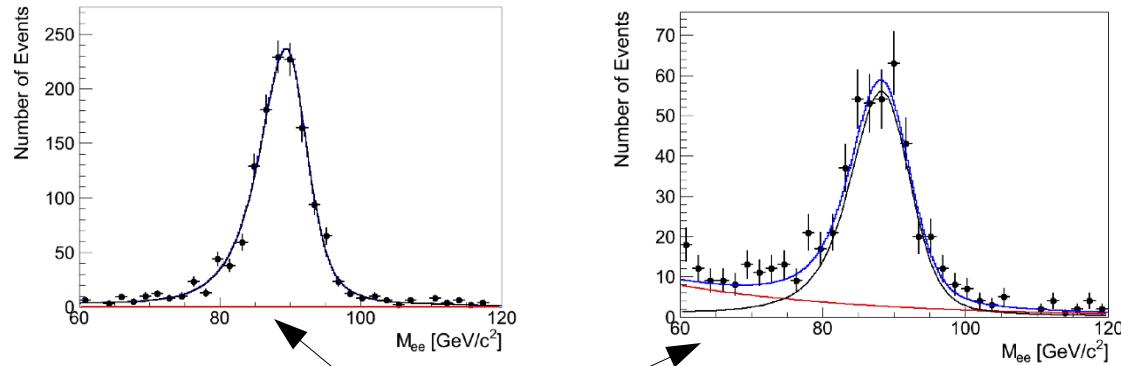
Example of MC test of the data-driven sample definitions

Tuning example with real data!



## Electron Selection Efficiency

- Electron selection efficiency is measured from data using a pure electron sample from Z decays (Tag-and-Probe)
  - One well identified electron tags the event and a second electron (probe) is used to estimate the efficiency
  - Efficiency is estimated by a template fit of the tag+probe invariant mass spectrum for the tag+(probe passing selection) and the tag+(probe failing selection)



Example Fits:  
probes are reconstructed electrons that **pass** or **fail** WP80 selection

## Electron Selection Efficiency

- The W efficiency as it is measured using Z events is biased
  - Kinematic differences between the W and Z lead to differences of the efficiency of the same selection

To allow for these kinematic differences the measured efficiency is corrected using simulation:

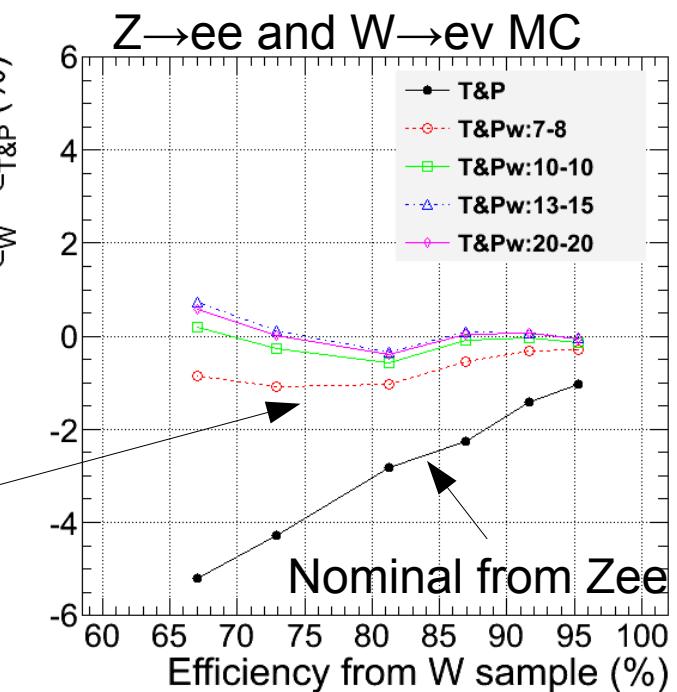
$$\epsilon_{sele} = \frac{\epsilon_{W, MC}}{\epsilon_{TP, MC}} \epsilon_{TP, DATA}$$

$\eta/E_T$  rescaled efficiency

Electron selection efficiency is estimated

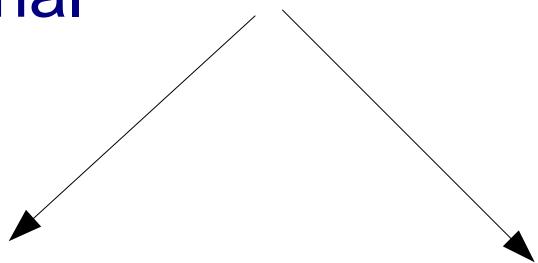
$$\epsilon_{sele} = 72.0 \pm 2.8 \%$$

(including electron reconstruction + trigger efficiencies)



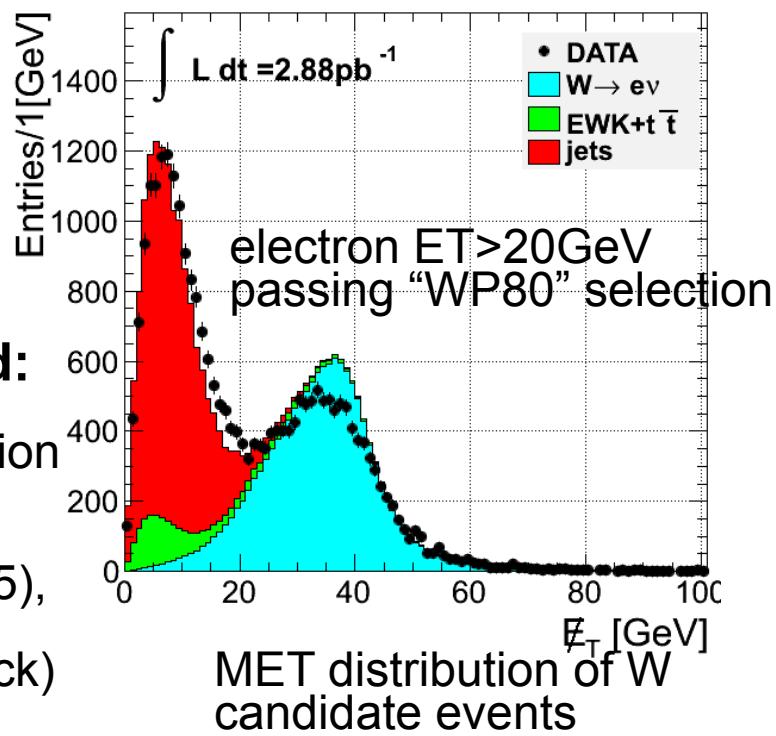
## Signal Extraction

- Despite the electron selection the final collection of  $W$  candidates contains a considerable amount of background
- Different methods to extract the signal



**“Template”-based:**  
Estimate signal and bkg shapes and extract the signal from a fit  
e.g. this study

**“Extrapolation”-based:**  
Extrapolate bkg to signal region from a bkg-rich region  
e.g. D0  $W$  width (2000),  
CDF  $W, Z$  production (2005),  
CMS-PAS-EWK-09-004,  
this study (as a cross-check)



# ‘Template’-based Signal Extraction

- What it is all about:
  - Estimate somehow the MET shape of the components of the  $W$  candidate sample
  - Perform a fit to the data to extract the number of signal events

$$Nf_{DATA}(MET) = N_{jet} f_{jet}(MET) + N_W f_W(MET)$$

Many options on how to construct templates

**Data-driven:**  
using a selection that rejects signal

**Ansatz-based:**  
assuming a priori a functional form

**Data-driven:**  
using Zee events

**Simulation-based:**  
needs corrections for possible differences in MET resolution between data-MC

## “Template”-based Signal Extraction

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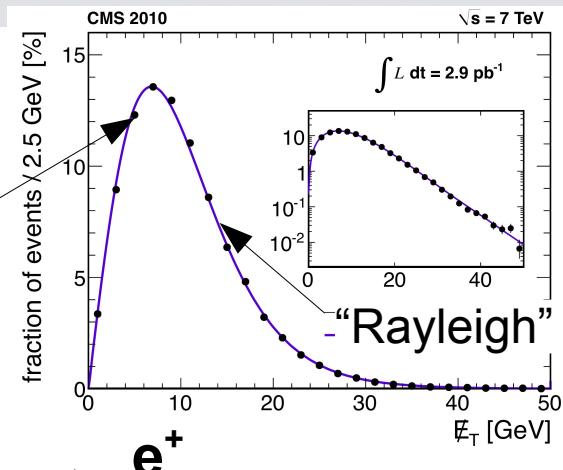
**Selected templates for the final result**  
(the other methods used as a cross-check when lumi allows)

## “Template”-based Signal Extraction

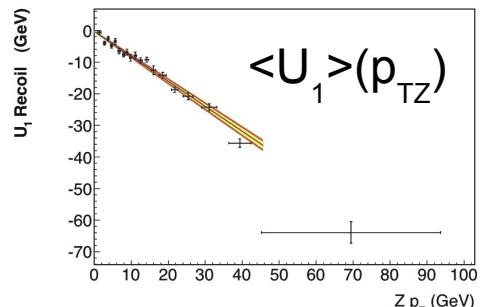
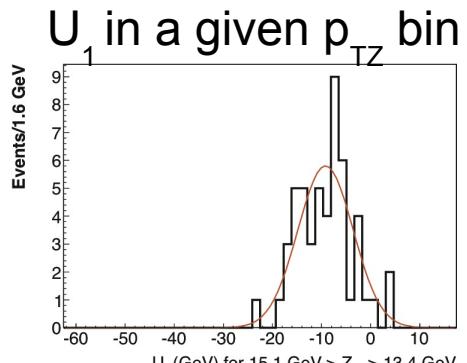
- Jet “template”: physics-motivated Rayleigh function ansatz

$$P_{jet}(x; \sigma_0, \sigma_1) = x \exp \left( -\frac{x^2}{2(\sigma_0 + \sigma_1 x)^2} \right),$$

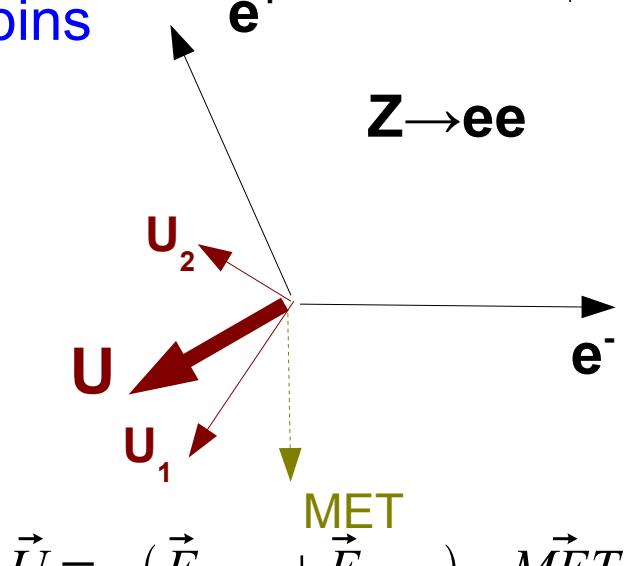
Data-driven  
(points)



- W “template”: from simulation
  - model from data the components of  $U$  in bins of boson  $p_T$  assuming gaussian behavior
  - correct the Wev simulation



Example recoil fits on  $Z$  data



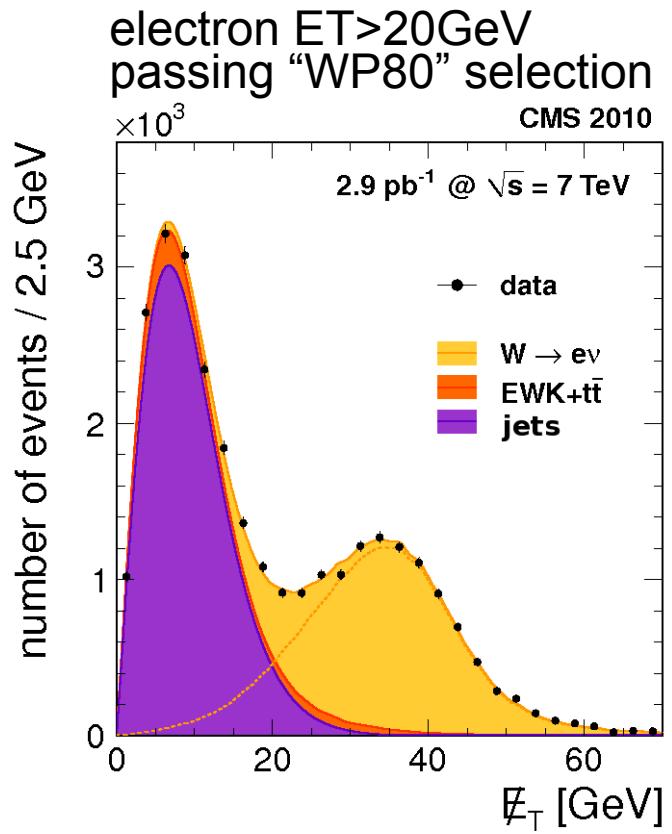
## “Template”-based Signal Extraction

- Other bkggs apart from jets are modeled directly from simulation and added to the signal “template”
  - Most important processes:  $W \rightarrow \tau\nu$ ,  $Z \rightarrow \tau\tau$ , top production
  - contribute  $\sim 13\%$  of signal yield
- Excellent agreement with data

**Number of signal events from the fit:**

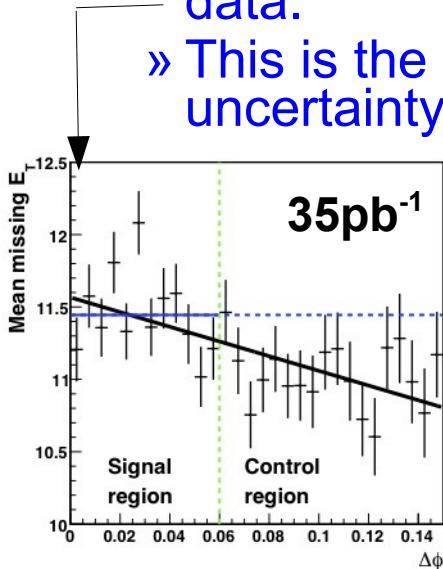
$$N = 11\,895 \pm 115$$

**(statistical uncertainty only)**

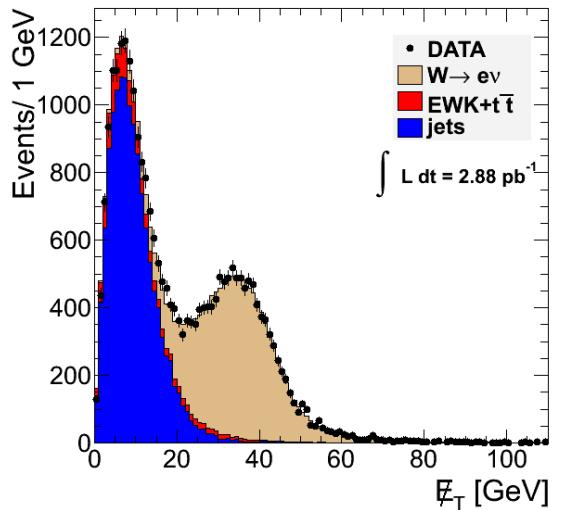


## Data-driven Jet-“template”

- Data-driven jet “templates” have been used as a cross-check of the result
  - Defined by a selection that rejects signal: invert track-ECAL cluster matching cuts ( $\Delta\eta$  and  $\Delta\phi$ )
  - Assumption: the inverted cuts are uncorrelated with MET
    - » And this is not quite true: possible to derive a correction with more data.
    - » This is the major source of systematic uncertainty of this method



With  $3\text{pb}^{-1}$  the result using this jet template is in agreement with the Rayleigh “template” within 1.2%



## “Extrapolation-based” signal extraction

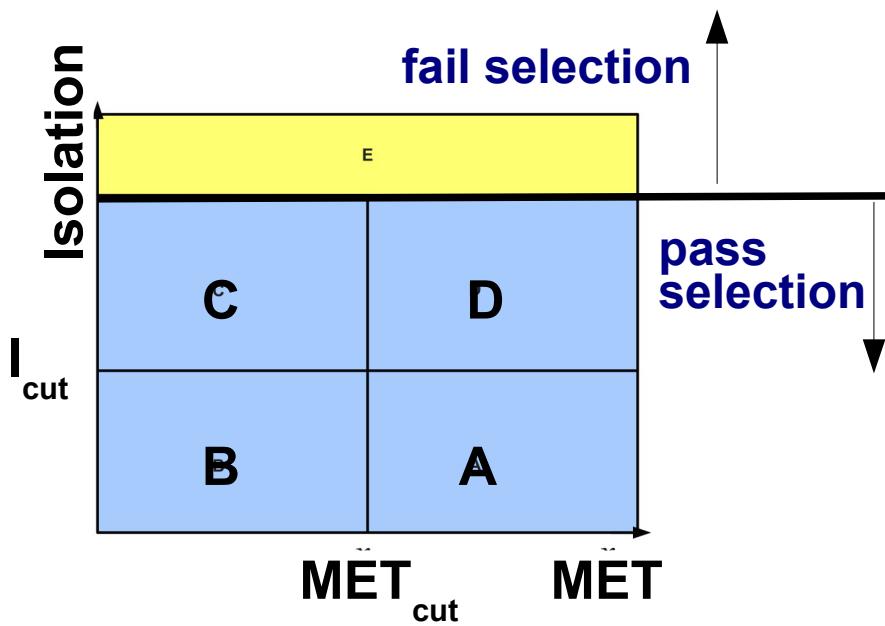
- Benchmark method in the CMS before data taking
- Based on finding 2 uncorrelated variables as far as the jet distribution is concerned: here MET and Isolation

Inputs of the method:

1. Events in A,B,C,D regions (from data)
2. MET efficiencies for signal events:  
 $\epsilon_A = S_A / S_{AB}$ ,  $\epsilon_D = S_D / S_{CD}$   
 (signal MET template needed)
3. Isolation efficiency for signal  
 $\epsilon_P = S_P / S_{ABCD}$   
 (Tag-and-Probe from Z electrons)

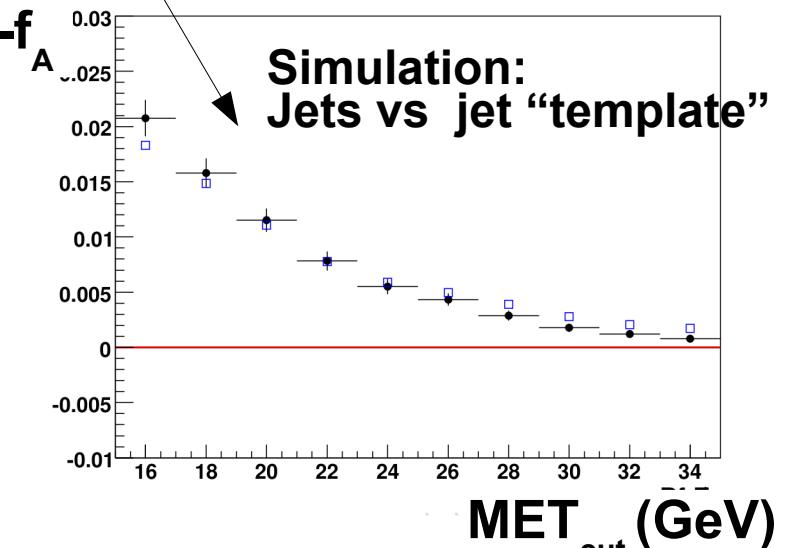
By assuming that for jet events  
 $f_A \equiv Q_A / Q_{AB} = f_D \equiv Q_D / Q_{CD}$

(i.e. jet shape extrapolation from CD to AB)  
 The total signal  $S_{ABCD}$  can be extracted



## “Extrapolation-based” signal extraction

- Jet shape assumption  $f_A = f_D$  does not hold exactly
  - This will result in a biased predicted number of signal events
  - A correction can be derived from data using the shapes from the data-driven jet “template”



But for all these you really need DATA,  
more data than  $3\text{pb}^{-1}$

With  $36\text{pb}^{-1}$  a data-driven correction of about 0.4% was derived  
The overall systematic in the signal extraction is 1.2% (very  
preliminary) and dominated by efficiency uncertainties

## Systematics

- Total systematic uncertainty (without luminosity error)  
~5%
  - c.f. Statistical error: 1% and luminosity error: 11%

**This figure will become smaller with more data**

either because of their statistical nature or due to the fact that more data will permit the implementation of other methods

source	uncertainty value (%)
Efficiency	3.9
PDF uncertainty on acceptance	0.8
Theoretical uncertainties on acceptance	1.3
Electron energy scale/resolution	2.0
Jet $\cancel{E}_T$ shape modelling	1.3
Signal $\cancel{E}_T$ shape modelling	1.8
Total	5.1

Highest systematic in the efficiency measurement: most of it is of statistical nature

Electron energy scale determined from Zee

“template” related errors  
~2.2% (more data will allow other potentially more accurate methods)

## Cross-Section Measurement ( $3\text{pb}^{-1}$ )

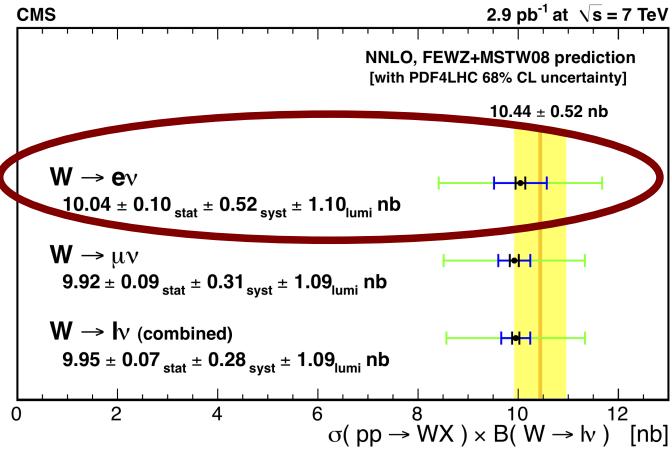
- Results:  $N_{\text{candidates}} - N_{\text{bkg}} = 11895 \pm 115 (\text{stat})$

$$\sigma = \frac{N_{\text{candidates}} - N_{\text{bkg}}}{A \epsilon \int L dt}$$

$$A = 0.571 \pm 0.09 (\text{theory})$$

$$\epsilon = 0.720 \pm 0.028$$

$$\int L dt = 2.88 \pm 0.32 \text{ pb}^{-1}$$



- Final result in very good agreement with theory

$$\sigma(pp \rightarrow W + X) \times BR(W \rightarrow e\nu) = 10.04 \pm 0.10 (\text{stat}) \pm 0.52 (\text{syst}) \pm 1.10 (\text{luminosity}) \text{ nb},$$

- Combined electron+muon result for the ratio

$$\frac{\sigma_W Br(W \rightarrow l\nu)}{\sigma_Z Br(Z \rightarrow ll)} = 10.64 \pm 0.40$$

**Sensitive to  $\Gamma_W$  at about 4% level!**  
(c.f. 2% all direct measurements combined)

## Prospects for the Future

- Still room for improvement in the systematics
  - Electron selection efficiency and energy scale are determined from Z data, which are statistically limited
  - **Preliminary** results suggest that template systematics also reduced with more data, e.g.
    - » data-driven jet template is at 0.6% (c.f. currently: 1.3%)
    - » “extrapolation-based” signal extraction is about 1.2% (c.f. Currently: 2.2  $\pm$  2%)
- New cross-section measurement with  $\sim 35\text{pb}^{-1}$  ongoing

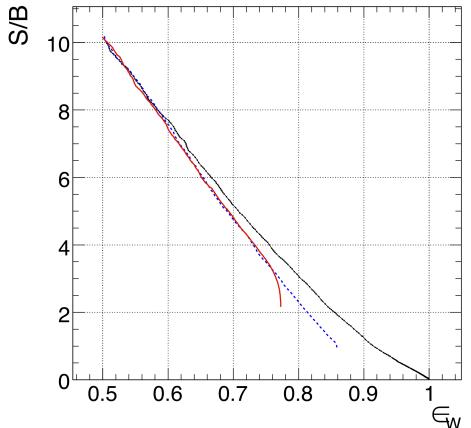
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  - And to you for your attention!

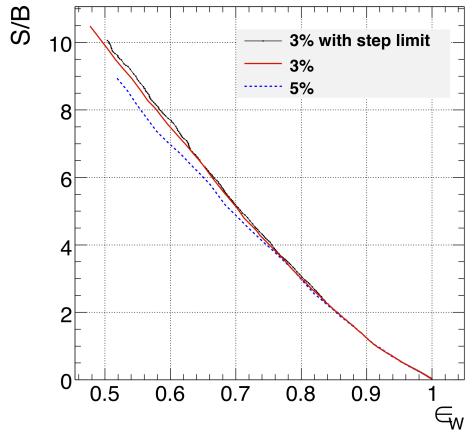
## Additional Slides

## “Iterative Technique” internal parameter tuning

- The algorithm internal parameters have to be chosen appropriately in order to achieve the optimal performance



Initial Conditions



Step convergence